

Notice of References Cited	Application/Control No. 09/767,459		Applicant(s)/Patent Under Reexamination AIZAWA ET AL.	
	Examiner Tran N. Nguyen		Art Unit 2834	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
X	A	US-5,843,567	12-1998	Swift et al.	428/221
	B	US-			
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	D	US-			
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	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	O	JP abstract 361186402	08-1986	Japan	Takagi	H01F001/08
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